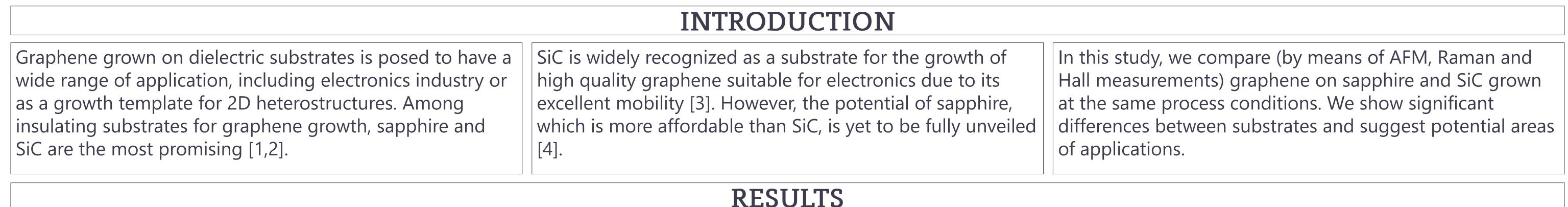
Characterization of wafer-scale CVD graphene grown on sapphire and SiC: a direct comparison

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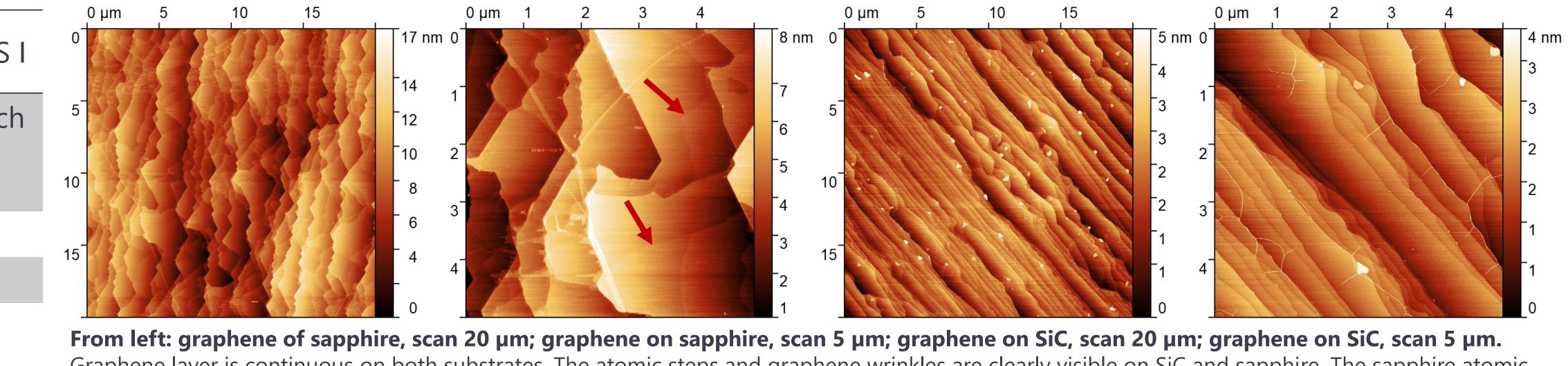
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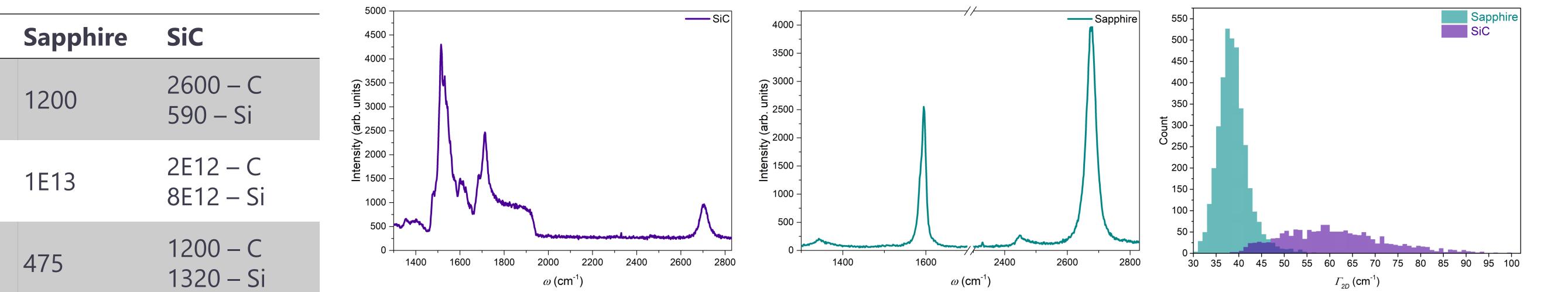
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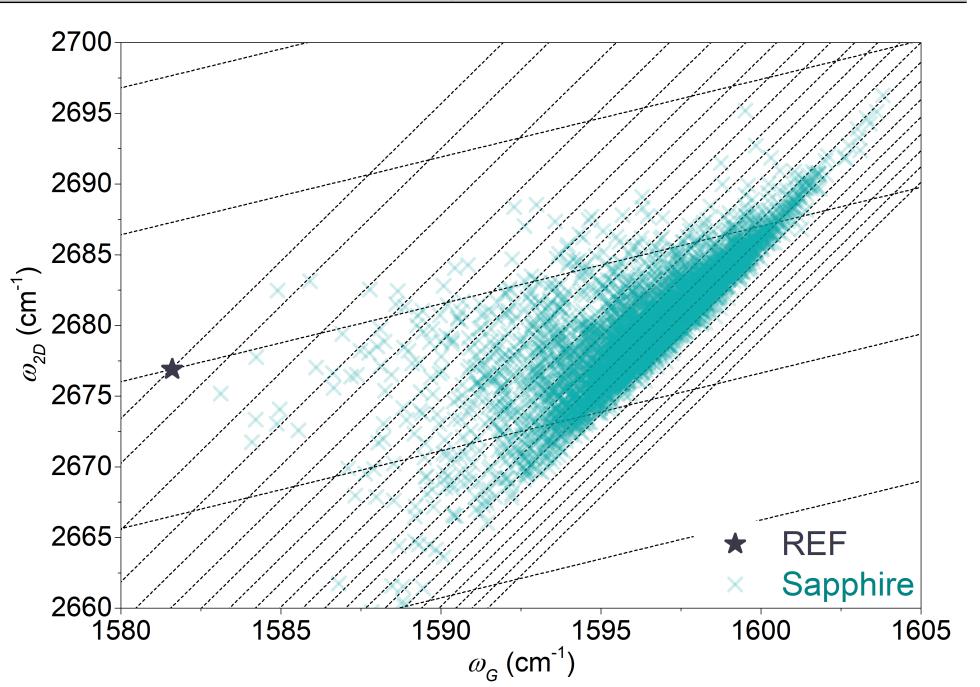
				0 µm	5	10	15		0 µ
Type of reactor	CVD CC	S AIXTRON	CRIUS I	0				17 nm	
Material	 Sapphire c-plane, 2-inch 6H-SiC 10×10 mm, C- and Si-face 							- 12 10 8	1 2 2
Pressure	700 mbar			15				6 - 4	5
Temperature	1560°C						XSA	-	4
Carbon source	Methane 240 s			From left: graphene of sapphire, scan 2 Graphene layer is continuous on both sub steps are much wider than on SiC, which is (red arrows). The number of wrinkles is slig					
Growth time									
	Electri	cal results							
Property		Sapphire	SiC		5000 - 4500 -				
Mobility [cm²/Vs]		1200	2600 – 590 – S		4000 - - 3500 - - 3000 - - 3000 - - 2500 - - 2000 - - 1500 -				
Carrier concent [1/cm ²]	ration	1E13	2E12 – 8E12 –		- 1000		W		
Sheet resistanc $[\Omega/\Box]$	е	475	1200 – 1320 –		500 - 0 -		1600 1800	2000 <i>ω</i> (cm ⁻¹	 2200 ')



rates. The atomic steps and graphene wrinkles are clearly visible on SiC and sapphire. The sapphire atomic avourable as it induces less strains. On sapphire, however, a considerable amount of second layer is present tly higher on SiC, indicating higher level of strain.

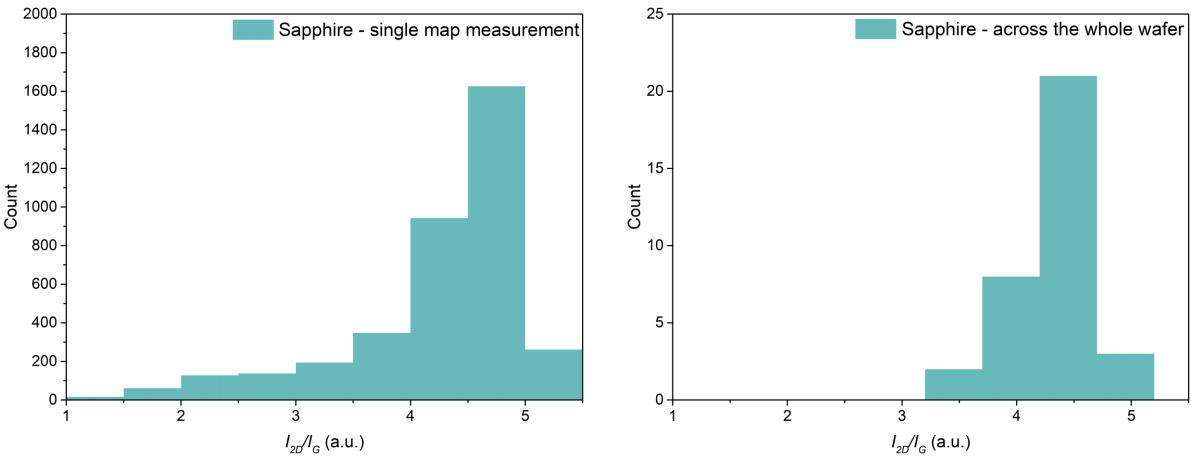
Raman characterization





Left and middle: exemplary Raman spectra of graphene on SiC and sapphire, respectively. **Right: Full width at half maximum (FWHM) of 2D peak.**

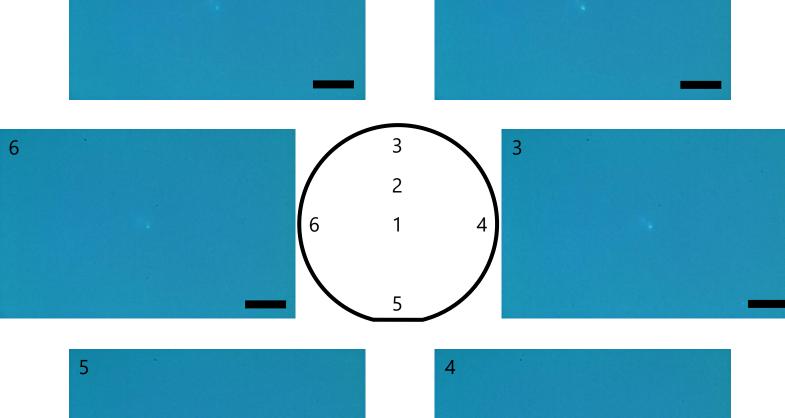
A visible D peak is present in graphene on sapphire, but it is not very intensive ($I_D/I_G = 0.1$). Since SiC peaks are at the same position as graphene G peak, it is not possible to estimate strain and doping levels. Therefore, the main quality factor is FWHM, which is significantly higher than for graphene on sapphire.

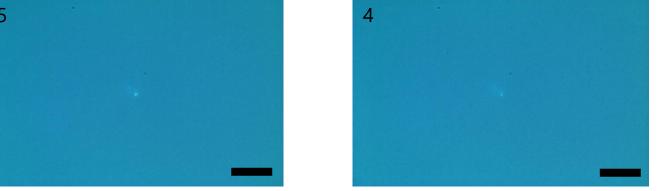


Strain-doping correlation for graphene on sapphire. The estimated doping level (which are approx. 1.4E13 1/cm²) is slightly higher than obtained in Hall measurements. Stress level is almost negligible (0 to 0.1%), which is favourable for application as a growth template.

Top: I_{2D}/I_{G} ratio – across one scan area (10×10 µm, 1600 points, left) and across the whole wafer (36 points, right).

Right: optical uniformity across the whole 2-inch wafer. Scale bars are 10 µm. Both Raman intensities and optical images are confirming high uniformity and quality of the graphene across the whole wafer.





CONCLUSIONS

It is possible to achieve uniform graphene monolayer on both SiC and sapphire using the same growth conditions, however, the growth needs to be performed at a very high temperature (1560°C). The are distinct differences between

Graphene wrinkles are present on both substrates. AFM showed small amount of add-layer on sapphire. Raman studies indicate that graphene grown on sapphire is of much higher structural quality, with low strain levels.

Graphene on sapphire is more uniform and of higher quality than graphene on SiC, however, due to low electrical performance it is insufficient for the use in electronics industry. Nevertheless, there are other potential fields of applications, for example growth of 2D heterostructures.

graphene	grown on	SiC and	sapphire.	

Electron mobility is better on SiC, but still relatively low.

THE BOTTOM LINE

Graphene grown on SiC and sapphire has relatively low electrical performance. Nonetheless, graphene on sapphire, due its uniformity and high structural quality, might be used as a growth template for 2D heterostructures.

LITERATURE

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